

AMENDMENT TO THE SPECIFICATION:

Please amend the following specification paragraphs as indicated.

Page 7, lines 6-8: please delete the paragraph and substitute therefore with following paragraph:

The invention also encompasses masks repaired, ~~enhancee enhanced~~, and fabricated by these methods. The invention also provides methods of using scanning probe microscopy to repair and fabricate masks by additive repair and additive lithography, respectively.

Pages 7-8 beginning on line 30: please delete the entire paragraph and substitute therefore with following paragraph:

Examples include but are not limited to (xiv) the deposition of and/or filling ~~with e.g.~~ with with e.g. (a) a metal-rich material, such a metal or an alloy, and precursors thereof; (b) a carbon-rich material, such as graphite-like carbon (including fullerenes and carbon nanotubes and carbon nanotube derivatives), and diamond-like carbon; (c) colloidal particles, including metallic ones; and mixtures containing thereof, (d) one or more high-molecular-weight compound(s), including organic and inorganic polymers, with or without the addition of colloidal particles; (xv) the deposition of metal oxide, glasses, silicates and related materials; (xvi) the sequential deposition / filling materials according to xiv) and xv) (multilayer formation) with, optionally, control of the thickness and roughness of each layer, as well as the edge geometry.